



PSB Singapore

# CERTIFICATE

The Certification Body  
of TÜV SÜD PSB Pte Ltd

certifies that

## STATS CHIPAC PTE LTD

5 Yishun Street 23  
Singapore 768442

has established and applies  
a Quality Management System for

1. Design and Development of ICs Package and Test Hardware and Software
2. Wafer Sort, Wafer Process, Assembly and Test of ICs
3. Packages WLCSP (Wafer Level Chip Scale Packages), Bump and Integrated Passive Device and eWLB (Embedded Wafer Level Ball Grid Array)

(See Appendix to Certificate for Details)

Proof has been furnished that the requirements  
according to

## ISO 9001 : 2015

are fulfilled. The certificate is valid from **2018-08-23** to **2021-08-22**

Certificate Registration No. **96-2-0622**

Date of Print : **2018-08-24**



SIEW Kwai Heng, Tiffany  
Certification Manager  
Business Assurance Division  
Management Systems



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Please refer to [www.tuv-sud-psb.sg](http://www.tuv-sud-psb.sg) for current certificate status in the "Directory of Management System Certified Companies".

TÜV SÜD PSB Pte Ltd • 1 Science Park Drive • Singapore 118221

TÜV®

ZERTIFIKAT ♦ CERTIFICATE ♦ 認證證書 ♦ СЕРТИФИКАТ ♦ CERTIFICADO ♦ CERTIFICAT



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# APPENDIX

To Certificate Number: 96-2-0622

Issue Number : 8  
 Date of Print : 2018-08-24  
 Issued to : **STATS CHIPPAC PTE LTD**  
 5 Yishun Street 23  
 Singapore 768442

**Process or service in respect of which the company is Certified:**

1. Design and Development of ICs Package and Test Hardware and Software
2. Wafer Sort, Wafer Process, Assembly and Test of ICs
3. Packages WLCSP (Wafer Level Chip Scale Packages), Bump and Integrated Passive Device and eWLB (Embedded Wafer Level Ball Grid Array)

**Process Detail(s)/Location(s):**

The scope of certification covers the following :

Divisions/ Locations	Supporting Functions
<b>Stats ChipPac Pte Ltd</b> 10 Ang Mo Kio Street 65, Techpoint, #04-08/09 Singapore 569059	Contract Review



SIEW Kwai Heng, Tiffany  
 Certification Manager  
 Business Assurance Division  
 Management Systems



Member of the IAF MLA for QMS